Abstracts

Computer-Aided Characterization of Millimeter-Wave Semiconductor Devices

H.J. Kuno, T.T. Fong and D.L. English. "Computer-Aided Characterization of Millimeter-Wave Semiconductor Devices." 1971 G-MTT International Microwave Symposium Digest of Technical Papers 71.1 (1971 [MWSYM]): 122-123.

A new, improved characterization technique for evaluating semiconductor devices at millimeter-wave frequencies is described. By this technique both passive and active parameters of the device (e.g., series resistance, junction capacitance, negative resistance), and also the circuit parasitic can be characterized accurately.

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